

Form PTO-1449  
REV. 1-2000

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

SERIAL NO.

LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Johr & Tiwald

FILING DATE

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
MD	AA	6573999	6/2003	Yang	356	632	
MD	AB	6349594	2/2002	Yabe	73	150	
	AC	5484701	1/1996	Norton et al.	250	372	
MD	AD	5798837	8/1998	Aspner et al	356	369	
	AE	4105338	8/1978	Kuroh	356	118	
	AF	5181080	1/1993	Fanton et al	356	369	
	AG	4826321	5/1989	Coater et al.	356	351	
	AH	5910842	6/1999	Piwonka-Gide et al	356	369	
	AI	5517312	5/1996	Fingrov	356	386	
	AJ	6278519	8/2001	Rosenchans et al	356	369	
MD	AK	4899055	2/1990	Adams	250	372	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

MD	AR	Opstal et al Pub No US 2002/0176081 A1, Nov. 28, 2002, Serial No. 10/138,984
	AS	

EXAMINER /Marissa Detschel/

DATE CONSIDERED 05/24/2006

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<b>LIST OF PRIOR ART CITED BY APPLICANT</b> (Use several sheets if necessary)		APPLICANT <u>John &amp; Tward</u>	
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EXAMINER INITIAL	AA	AB	AC	AD	AE	AF	AG	AH	AI	AJ	AK	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
MD												5798837	8/1998	Aspner et al.	358	369	
												5793480	8/1998	Lacey et al.	358	27	
												590093	9/1999	Aspner et al.	358	369	
												5595916	1/1997	Fujimura et al.	437	8	
												6605482	8/2003	Celii et al.	438	16	
V												6278809	8/2001	Johnson et al.	385	17	
MD												5871805	2/1999	Lenelson	427	8	

**FOREIGN PATENT DOCUMENTS**

AL	AM	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

MD	AR	Data Analysis for Spectroscopic Ellipsometry, Thin Solid Films 234 (1993) by Jellison Jr.
	AS	

EXAMINER /Marissa Detschel/	DATE CONSIDERED 05/24/2006
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